

# EAST Search History

10/520,729

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	4336734	semiconductor or integrated adj circuit\$1 or ic\$1 or die\$1 or dice\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 07:46
L2	968486	1 and light	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 07:46
L3	20146	2 and focus\$4 near beam	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 07:47
L4	12213	3 and scan\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 07:47
L5	25	4 and high\$1contrast near imag\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 07:55
L6	9644	4 and imag\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 07:56
L7	161	6 and (obic or optical near beam near induc\$4 near current\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 07:57